

Notice of References Cited	Application/Control No. 10/715,475	Applicant(s)/Patent Under Reexamination CHAO, YUAN-JEN	
	Examiner Kimnhung Nguyen	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0003522	01-2002	Baba et al.	345/89
*	B	US-6,943,784	09-2005	Kuo et al.	345/204
*	C	US-5,786,801	07-1998	Ichise, Atsushi	345/102
*	D	US-2001/0013854	08-2001	Ogoro, Kazuo	345/102
*	E	US-2004/0012556	01-2004	Yong et al.	345/102
*	F	US-7,106,350	09-2006	Baba et al.	345/691
*	G	US-2003/0090455	05-2003	Daly, Scott J.	345/102
*	H	US-2002/0044116	04-2002	Tagawa et al.	345/87
*	I	US-2002/0036608	03-2002	Hirakata et al.	345/87
*	J	US-2002/0030660	03-2002	Arakawa, Satoshi	345/102
*	K	US-2003/0020677	01-2003	Nakano, Takao	345/87
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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